Rockley Photonics Manufacturing Ecosystem





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EPIC Online Technology Meeting on Automated Packaging & Testing of Photonic Integrated Circuits

Developing Full Wafer Level Back-End



- Convert from Die-to-Die (D2D) to Die-to-Wafer (D2W) AuSn bonding
- Eliminates die touching
- Major reduction in time to locate next bond position
- Die location improved (lithography vs fixture)
- Eliminates expensive die level fixturing

- Enables rest of back end to be automated at wafer level
- Wafer level underfill dispense
- Enables wafer level burn-in with precise contact alignment
- Enables high speed electrical-optical test
- Stealth dicing: Clean, no particulate; close facet proximity without damage; High yield; Consistent stretch for automated PnP; Qualified

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PHOTONICS

Critical Assembly Processes and Capabilities



- High accuracy AuSn bonding (XY)
- Height/tilt control (Z)
- Index matching underfill gel for light coupling and reduced back reflection
- Reliable, short, low-loop wire bonds for high-speed performance
- Low-loss, long-life, passive fiber attach for ease of assembly
- Back-end automation





AuSn Bonding



- Metal alloy control pre and post bonding
- X/Y post bond location accuracy +/-0.5um
- Requires fiducials with consistent appearance to bonder and in fab layers of feature that require alignment
- Vertical alignment control by passive design with structure







T. B.Massalski Editor-in-chief, Binary Alloy Phase Diagrams, ASM, (1984), pp.315-317.



X/Y plane view of optical "gap"

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Index Matching Gel to improve Light Coupling and Reduce Back Reflection





Uniform UF fillet 10~20um wide

• Challenges:

- Small die size \rightarrow 2nL dispense
- 100um die thickness
- No material on die backside
- Fill significant topology in between III-V and Si
- No voids allowable in optical gap



Beam divergence is reduced with use of higher-index matching fluid

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Wirebond



- Short length for optimum RF performance
- Loop necessary to compensate for height difference between TIA and PIC in QSFP-DD module
- Matched pitch between ICs to eliminate added length from fan-out
- Small bond pad sizes



wirebonds

Gap between ICs

X

SMF-28 Fiber



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Fiber Attach

- Passive fiber attach
- Narrow mode matching converter to fiber interface to optimize coupling
- <0.5 dB coupling loss
- 2,000 hours 85/85 plus temp cycle and 2 cycles of solder reflow

BIT WG







Rockley Photonics Health Sensors



- Unique sensing platform targeting applications in consumer health and wellness → driving an exponential increase in application capabilities for non-invasive, multi-modal biomarker monitoring
- Built on Rockley's integrated silicon photonics technology
- Internally designed lasers generate numerous wavelengths of light: Visible and IR spectrum
- Light is directed into/reflected from the skin
- Reflected light is gathered by photo detectors and spectral absorption analyzed



Unique Spectrometer Chip

Mobile LED technology:

- An effective light source for resolving blood components with strong absorbance signatures in the visible and near IR range
- Falls short in power efficiency, signal strength, and spectral range and resolution for targeted biomolecule quantification, in blood, tissue, and skin

"Clinic-on-the-Wrist" *Condensing technology the size of clinical machines onto a wearable chip



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